

Battery contacting probe

BCP-655 360 1800 A 100004M-53

Item BCP-655-0003

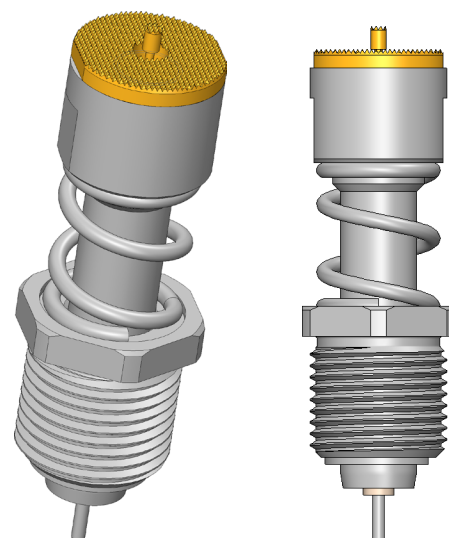


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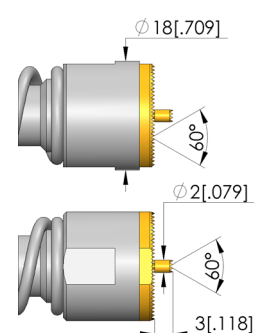
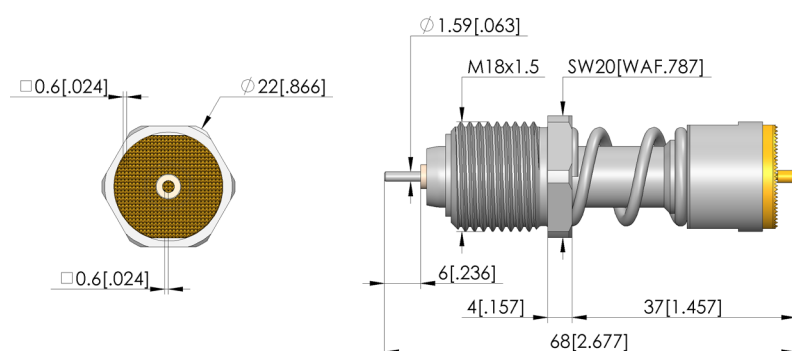
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- Contact solution for 4680 cylindrical cells and prismatic cells
- Suitable for currents up to 125 A at $\Delta T \leq 20$ K on aluminium
- Low-impedance probe with typical total resistance < 0.5 mOhm
- Designed for a wide range of applications, especially for formation and other end-of-life (EOL) tests
- Fixed cable connection
- Easy installation via threaded connection, secure hold in busbar
- Dipole design for precise voltage measurement
- Easy connection of the voltage sensor: both soldering and cable lug installation possible



1:1



General data

Screw-in torque max.:	2,000 cNm [177 lbf-in]
Product group:	Dipole BCP / 4-wire clamp
Sub-product group:	Dipole BCP / 4-wire clamp
Series:	BCP-655 M screw-in
Grid:	30 mm [1,181 mil]
Contacting from:	Post
Magnetic:	Yes
Installation type:	Screw-in
Quick-exchange system:	No
Type of test probe connection:	Thread connection
Adjustable installation height:	No
Non-rotating:	No
Min. temperature:	-40 °C [-40 °F]
Max. temperature:	80 °C [176 °F]
RoHS-compliant:	Yes

Tip style data

Tip style:	60 serrated, small grid
Tip diameter:	18 mm [0.708 in]
Tip style surface:	A gold
Tip style material:	3 CuBe

Electrical data

Current load capacity / rated current:	125 A
Typical resistance (Ri):	1 mOhm

Mechanical data

Total length:	68 mm [2.67 in]
Barrel diameter:	18 mm [0.708 in]
Maximum stroke:	7 mm [0.275 in]
Spring pre-load:	47.6 N [171 ozf]
Collar height:	04
Spring force at working stroke:	100 N [359 ozf]
Recommended working stroke:	4.4 mm [0.173 in]

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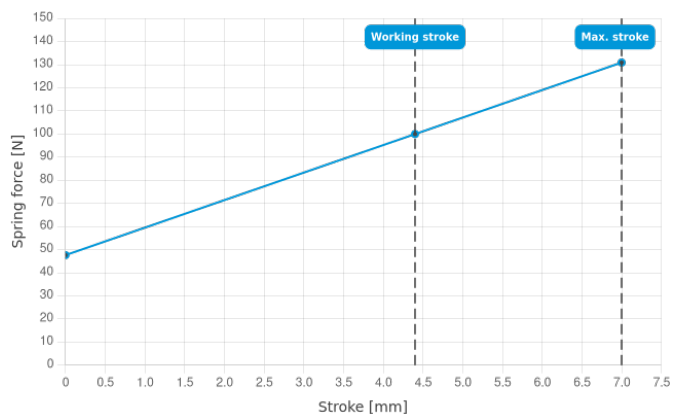
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